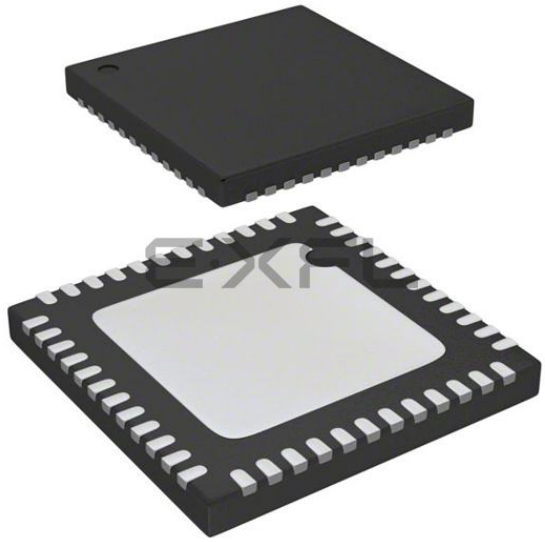

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	84MHz
Connectivity	I²C, IrDA, LINbus, SDIO, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	36
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	96K x 8
Voltage - Supply (Vcc/Vdd)	1.7V ~ 3.6V
Data Converters	A/D 10x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-VFQFN Exposed Pad
Supplier Device Package	48-UFQFPN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f401ceu6tr

3.15.3 Regulator ON/OFF and internal power supply supervisor availability

Table 3. Regulator ON/OFF and internal power supply supervisor availability

Package	Regulator ON	Regulator OFF	Power supply supervisor ON	Power supply supervisor OFF
UFQFPN48	Yes	No	Yes	No
WLCSP49	Yes	No	Yes PDR_ON set to VDD	Yes PDR_ON external control(1)
LQFP64	Yes	No	Yes	No
LQFP100	Yes	No	Yes	No
UFBGA100	Yes BYPASS_REG set to VSS	Yes BYPASS_REG set to VDD	Yes PDR_ON set to VDD	Yes PDR_ON external control (1)

1. Refer to *Section 3.14: Power supply supervisor*

3.16 Real-time clock (RTC) and backup registers

The backup domain includes:

- The real-time clock (RTC)
- 20 backup registers

The real-time clock (RTC) is an independent BCD timer/counter. Dedicated registers contain the second, minute, hour (in 12/24 hour), week day, date, month, year, in BCD (binary-coded decimal) format. Correction for 28, 29 (leap year), 30, and 31 day of the month are performed automatically. The RTC features a reference clock detection, a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision. The RTC provides a programmable alarm and programmable periodic interrupts with wakeup from Stop and Standby modes. The sub-seconds value is also available in binary format.

It is clocked by a 32.768 kHz external crystal, resonator or oscillator, the internal low-power RC oscillator or the high-speed external clock divided by 128. The internal low-speed RC has a typical frequency of 32 kHz. The RTC can be calibrated using an external 512 Hz output to compensate for any natural quartz deviation.

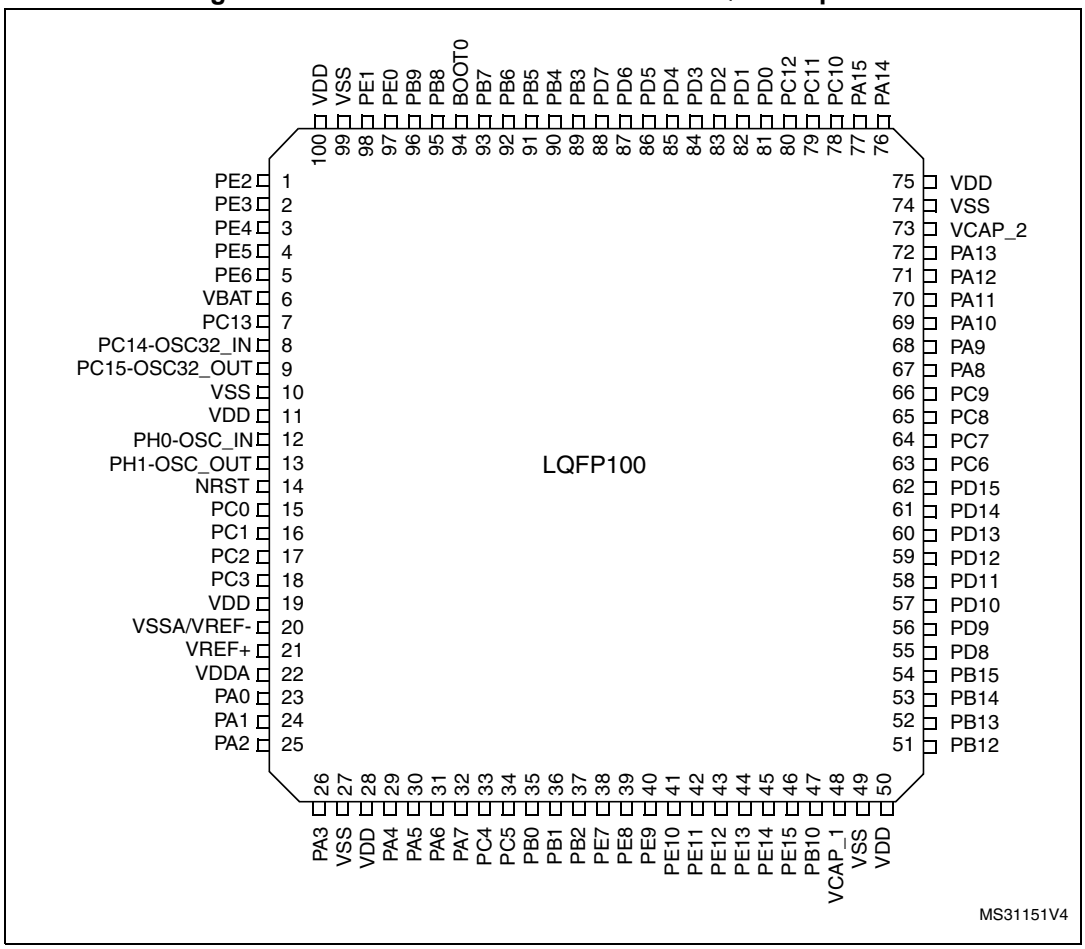
Two alarm registers are used to generate an alarm at a specific time and calendar fields can be independently masked for alarm comparison. To generate a periodic interrupt, a 16-bit programmable binary auto-reload downcounter with programmable resolution is available and allows automatic wakeup and periodic alarms from every 120 µs to every 36 hours.

A 20-bit prescaler is used for the time base clock. It is by default configured to generate a time base of 1 second from a clock at 32.768 kHz.

The backup registers are 32-bit registers used to store 80 bytes of user application data when V_{DD} power is not present. Backup registers are not reset by a system, a power reset, or when the device wakes up from the Standby mode (see *Section 3.17: Low-power modes*).

Additional 32-bit registers contain the programmable alarm subseconds, seconds, minutes, hours, day, and date.

Figure 13. STM32F401xB/STM32F401xC LQFP100 pinout



1. The above figure shows the package top view.

Table 9. Alternate function mapping (continued)

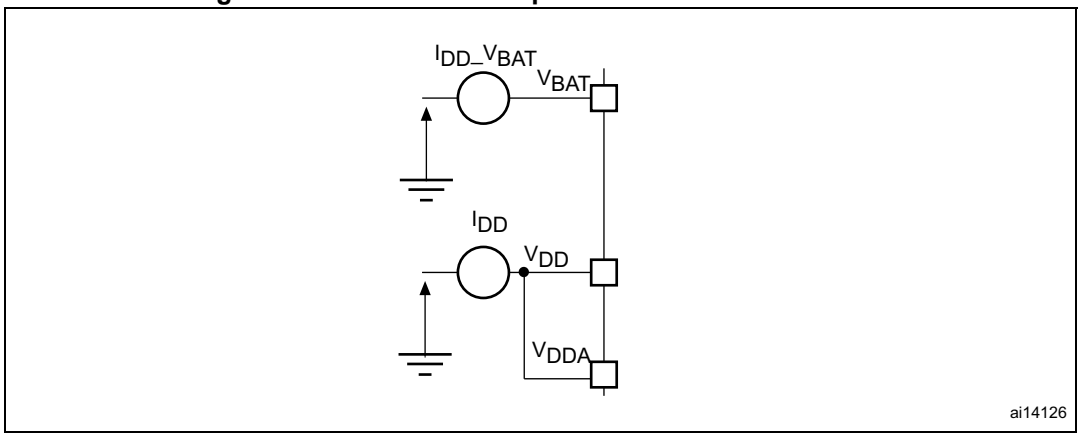
Port		AF00	AF01	AF02	AF03	AF04	AF05	AF06	AF07	AF08	AF09	AF10	AF11	AF12	AF13	AF14	AF15
		SYS_AF	TIM1/TIM2	TIM3/ TIM4/ TIM5	TIM9/ TIM10/ TIM11	I2C1/I2C2/ I2C3	SPI1/SPI2/ I2S2/SPI3/ I2S3/SPI4	SPI2/I2S2/ SPI3/ I2S3	SPI3/I2S3/ USART1/ USART2	USART6	I2C2/ I2C3	OTG1_FS		SDIO			
Port B	PB0	-	TIM1_CH2N	TIM3_CH3	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB1	-	TIM1_CH3N	TIM3_CH4	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB3	JTDO-SWO	TIM2_CH2	-	-	-	SPI1_SCK	SPI3_SCK/ I2S3_CK	-	-	I2C2_SDA	-	-	-	-	-	EVENT OUT
	PB4	JTRST	-	TIM3_CH1	-	-	SPI1_ MISO	SPI3_MISO	I2S3ext_SD	-	I2C3_SDA	-	-	-	-	-	EVENT OUT
	PB5	-	-	TIM3_CH2	-	I2C1_ SMBA	SPI1 _MOSI	SPI3_MOSI/ I2S3_SD	-	-	-	-	-	-	-	-	EVENT OUT
	PB6	-	-	TIM4_CH1	-	I2C1_SCL	-	-	USART1_ TX	-	-	-	-	-	-	-	EVENT OUT
	PB7	-	-	TIM4_CH2	-	I2C1_SDA	-	-	USART1_ RX	-	-	-	-	-	-	-	EVENT OUT
	PB8	-	-	TIM4_CH3	TIM10_CH1	I2C1_SCL	-	-	-	-	-	-	-	SDIO_ D4	-	-	EVENT OUT
	PB9	-	-	TIM4_CH4	TIM11_CH1	I2C1_SDA	SPI2_NSS/I 2S2_WS	-	-	-	-	-	-	SDIO_ D5	-	-	EVENT OUT
	PB10	-	TIM2_CH3	-	-	I2C2_SCL	SPI2_SCK/I 2S2_CK	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB11	-	TIM2_CH4	-	-	I2C2_SDA	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB12	-	TIM1_BKIN	-	-	I2C2_ SMBA	SPI2_NSS/I 2S2_WS	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB13	-	TIM1_CH1N	-	-	-	SPI2_SCK/I 2S2_CK	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB14	-	TIM1_CH2N	-	-	-	SPI2_MISO	I2S2ext_SD	-	-	-	-	-	-	-	-	EVENT OUT
	PB15	RTC_ REFN	TIM1_CH3N	-	-	-	SPI2_MOSI /I2S2_SD	-	-	-	-	-	-	-	-	-	EVENT OUT

Table 10. STM32F401xB/STM32F401xC register boundary addresses (continued)

Bus	Boundary address	Peripheral
APB1	0x4000 7000 - 0x4000 73FF	PWR
	0x4000 6000 - 0x4000 6FFF	Reserved
	0x4000 5C00 - 0x4000 5FFF	I2C3
	0x4000 5800 - 0x4000 5BFF	I2C2
	0x4000 5400 - 0x4000 57FF	I2C1
	0x4000 4800 - 0x4000 53FF	Reserved
	0x4000 4400 - 0x4000 47FF	USART2
	0x4000 4000 - 0x4000 43FF	I2S3ext
	0x4000 3C00 - 0x4000 3FFF	SPI3 / I2S3
	0x4000 3800 - 0x4000 3BFF	SPI2 / I2S2
	0x4000 3400 - 0x4000 37FF	I2S2ext
	0x4000 3000 - 0x4000 33FF	IWDG
	0x4000 2C00 - 0x4000 2FFF	WWDG
	0x4000 2800 - 0x4000 2BFF	RTC & BKP Registers
	0x4000 1000 - 0x4000 27FF	Reserved
	0x4000 0C00 - 0x4000 0FFF	TIM5
	0x4000 0800 - 0x4000 0BFF	TIM4
	0x4000 0400 - 0x4000 07FF	TIM3
	0x4000 0000 - 0x4000 03FF	TIM2

6.1.7 Current consumption measurement

Figure 19. Current consumption measurement scheme



6.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in *Table 11: Voltage characteristics*, *Table 12: Current characteristics*, and *Table 13: Thermal characteristics* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. Device mission profile (application conditions) is compliant with JEDEC JESD47 Qualification Standard. Extended mission profiles are available on demand.

Table 11. Voltage characteristics

Symbol	Ratings	Min	Max	Unit
V_{DD}–V_{SS}	External main supply voltage (including V_{DDA}, V_{DD} and V_{BAT})(1)	–0.3	4.0	V
V_{IN}	Input voltage on FT pins(2)	V_{SS}–0.3	V_{DD}+4.0	
	Input voltage on any other pin	V_{SS}–0.3	4.0	
	Input voltage for BOOT0	V_{SS}	9.0	
$\lvert\Delta V_{DDx}\rvert$	Variations between different V_{DD} power pins	-	50	mV
$\lvert V_{SSX} - V_{SS}\rvert$	Variations between all the different ground pins including V_{REF-}	-	50	
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	see *Section 6.3.14: Absolute maximum ratings (electrical sensitivity)*		

1. All main power (V_{DD}, V_{DDA}) and ground (V_{SS}, V_{SSA}) pins must always be connected to the external power supply, in the permitted range.
2. V_{IN} maximum value must always be respected. Refer to *Table 12* for the values of the maximum allowed injected current.

Table 12. Current characteristics

Symbol	Ratings	Max.	Unit
ΣI_{VDD}	Total current into sum of all V_{DD_x} power lines (source)(1)	160	mA
ΣI_{VSS}	Total current out of sum of all V_{SS_x} ground lines (sink)(1)	-160	
I_{VDD}	Maximum current into each V_{DD_x} power line (source)(1)	100	
I_{VSS}	Maximum current out of each V_{SS_x} ground line (sink)(1)	-100	
I_{IO}	Output current sunk by any I/O and control pin	25	
	Output current sourced by any I/O and control pin	-25	
ΣI_{IO}	Total output current sunk by sum of all I/O and control pins (2)	120	
	Total output current sourced by sum of all I/Os and control pins(2)	-120	
$I_{INJ(PIN)}$ (3)	Injected current on FT pins (4)	–5/+0	
	Injected current on NRST and B pins (4)		
$\Sigma I_{INJ(PIN)}$	Total injected current (sum of all I/O and control pins)(5)	±25	

1. All main power (V_{DD}, V_{DDA}) and ground (V_{SS}, V_{SSA}) pins must always be connected to the external power supply, in the permitted range.
2. This current consumption must be correctly distributed over all I/Os and control pins. The total output current must not be sunk/sourced between two consecutive power supply pins referring to high pin count LQFP packages.
3. Negative injection disturbs the analog performance of the device. See note in *Section 6.3.20: 12-bit ADC characteristics*.
4. Positive injection is not possible on these I/Os and does not occur for input voltages lower than the specified maximum value.
5. When several inputs are submitted to a current injection, the maximum $\Sigma I_{INJ(PIN)}$ is the absolute sum of the positive and negative injected currents (instantaneous values).

Table 13. Thermal characteristics

Symbol	Ratings	Value	Unit
T_{STG}	Storage temperature range	–65 to +150	°C
T_J	Maximum junction temperature	125	
T_{LEAD}	Maximum lead temperature during soldering (WLCSP49, LQFP64/100, UFQFPN48, UFBGA100)	see note (1)	

1. Compliant with JEDEC Std J-STD-020D (for small body, Sn-Pb or Pb assembly), the ST ECOPACK® 7191395 specification, and the European directive on Restrictions on Hazardous Substances (ROHS directive 2011/65/EU, July 2011).

6.3 Operating conditions

6.3.1 General operating conditions

Table 14. General operating conditions

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HCLK}	Internal AHB clock frequency	Power Scale3: Regulator ON, VOS[1:0] bits in PWR_CR register = 0x01	0	-	60	MHz
		Power Scale2: Regulator ON, VOS[1:0] bits in PWR_CR register = 0x10	0	-	84	
f_{PCLK1}	Internal APB1 clock frequency		0	-	42	
f_{PCLK2}	Internal APB2 clock frequency		0	-	84	
V_{DD}	Standard operating voltage		1.7(1)	-	3.6	V
V_{DDA} (2)(3)	Analog operating voltage (ADC limited to 1.2 M samples)	Must be the same potential as V_{DD}(4)	1.7(1)	-	2.4	
	Analog operating voltage (ADC limited to 2.4 M samples)		2.4	-	3.6	
V_{BAT}	Backup operating voltage		1.65	-	3.6	
V_{12}	Regulator ON: 1.2 V internal voltage on V_{CAP_1}/V_{CAP_2} pins	VOS[1:0] bits in PWR_CR register = 0x01 Max frequency 60 MHz	1.08(5)	1.14	1.20(5)	
		VOS[1:0] bits in PWR_CR register = 0x10 Max frequency 84 MHz	1.20(5)	1.26	1.32(5)	
V_{12}	Regulator OFF: 1.2 V external voltage must be supplied on V_{CAP_1}/V_{CAP_2} pins	Max. frequency 60 MHz.	1.1	1.14	1.2	
		Max. frequency 84 MHz.	1.2	1.26	1.32	
V_{IN}	Input voltage on RST and FT pins(6)	$2\ V \le V_{DD} \le 3.6\ V$	–0.3	-	5.5	
		$V_{DD} \le 2\ V$	–0.3	-	5.2	
	Input voltage on BOOT0 pin		0	-	9	
P_D	Maximum allowed package power dissipation for suffix 6 and 7(7)	UFQFPN48	-	-	625	mW
		WLCSP49	-	-	385	
		LQFP64	-	-	313	
		LQFP100	-	-	465	
		UFBGA100	-	-	323	

Table 23. Typical and maximum current consumption in run mode, code with data processing (ART accelerator enabled except prefetch) running from Flash memory - V_{DD} = 3.3 V

Symbol	Parameter	Conditions	f_{HCLK} (MHz)	Typ	Max(1)			Unit
					T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD}	Supply current in **Run mode**	External clock, all peripherals enabled(2)(3)	84	22.5	**23**	24	25	mA
			60	14.8	16	17	18	
			40	11.0	12	13	14	
			30	8.9	10	11	12	
			20	7.3	8	9	10	
		External clock, all peripherals disabled(3)	84	11.8	13	14	15	
			60	7.9	9	10	11	
			40	5.8	7	8	9	
			30	4.8	6	7	8	
			20	4.0	5	6	7	

1. Guaranteed by characterization, unless otherwise specified.
2. Add an additional power consumption of 1.6 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is ON (ADON bit is set in the ADC_CR2 register).
3. When the ADC is ON (ADON bit set in the ADC_CR2), add an additional power consumption of 1.6mA per ADC for the analog part.

.

Table 24. Typical and maximum current consumption in run mode, code with data processing (ART accelerator disabled) running from Flash memory

Symbol	Parameter	Conditions	f_{HCLK} (MHz)	Typ	Max(1)			Unit
					T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD}	Supply current in **Run mode**	External clock, all peripherals enabled(2)(3)	84	30.6	32	34	35	mA
			60	21.4	22	24	25	
			40	15.6	16	17	18	
			30	12.7	13	14	15	
			20	10.0	11	12	13	
		External clock, all peripherals disabled(3)	84	19.9	21	23	25	
			60	14.6	15	16	17	
			40	10.4	11	12	13	
			30	8.6	9	10	11	
			20	6.7	7	8	9	

1. Guaranteed by characterization, unless otherwise specified.
2. Add an additional power consumption of 1.6 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is ON (ADON bit is set in the ADC_CR2 register).
3. When the ADC is ON (ADON bit set in the ADC_CR2), add an additional power consumption of 1.6mA per ADC for the analog part.

Table 27. Typical and maximum current consumptions in Stop mode - V_{DD}=1.8 V

Symbol	Parameter	Conditions	Typ	Max(1)			Unit
			T_A = 25 °C	T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD_STOP}	Main regulator usage	Flash in Stop mode, all oscillators OFF, no independent watchdog	109	135	440	650	µA
	Low power regulator usage		41	65	310	530(2)	
	Main regulator usage	Flash in Deep power down mode, all oscillators OFF, no independent watchdog	72	95	345	530	
	Low power regulator usage		12	36	260	510(2)	
	Low power low voltage regulator usage		10	27	230	460	

1. Guaranteed by characterization.
2. Guaranteed by test in production.

Table 28. Typical and maximum current consumption in Stop mode - V_{DD}=3.3 V

Symbol	Parameter	Conditions	Typ	Max(1)			Unit
			T_A = 25 °C	T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD_STOP}	Main regulator usage	Flash in Stop mode, all oscillators OFF, no independent watchdog	111	140	450	670	µA
	Low power regulator usage		42	65	330	560	
	Main regulator usage	Flash in Deep power down mode, all oscillators OFF, no independent watchdog	73	100	360	560	
	Low power regulator usage		12	36	270	520	
	Low power low voltage regulator usage		10	28	230	470	

1. Guaranteed by characterization.

Table 29. Typical and maximum current consumption in Standby mode - V_{DD}=1.8 V

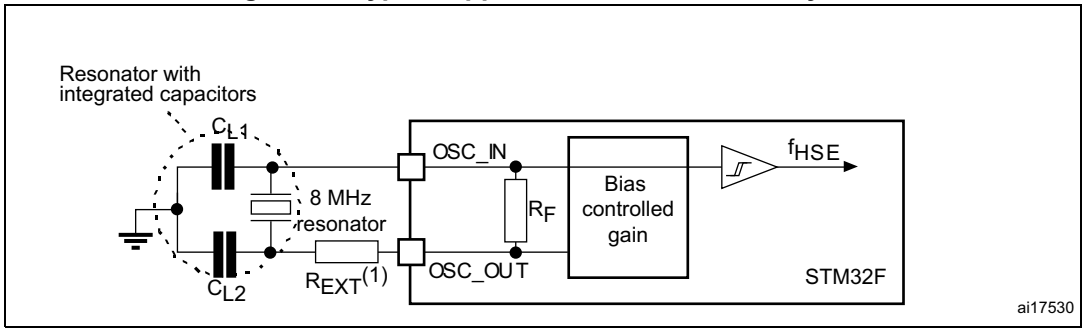
Symbol	Parameter	Conditions	Typ(1)	Max(2)			Unit
			T_A = 25 °C	T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD_STBY}	Supply current in Standby mode	Low-speed oscillator (LSE) and RTC ON	2.4	4.0	12.0	24.0	µA
		RTC and LSE OFF	1.8	3.0(3)	11.0	23.0(3)	

1. When the PDR is OFF (internal reset is OFF), the typical current consumption is reduced by 1.2 µA.
2. Guaranteed by characterization, unless otherwise specified.
3. Guaranteed by test in production.

series combination of C_{L1} and C_{L2}. PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing C_{L1} and C_{L2}.

Note: For information on selecting the crystal, refer to the application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.

Figure 24. Typical application with an 8 MHz crystal



1. R_{EXT} value depends on the crystal characteristics.

Low-speed external clock generated from a crystal/ceramic resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in *Table 38*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 38. LSE oscillator characteristics (f_{LSE} = 32.768 kHz) (1)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
R_F	Feedback resistor		-	18.4	-	MΩ
I_{DD}	LSE current consumption		-	-	1	µA
G_m_crit_max	Maximum critical crystal g_m	Startup	-	-	0.56	µA/V
$t_{SU(LSE)}$ (2)	startup time	V_{DD} is stabilized	-	2	-	s

1. Guaranteed by design.
2. $t_{SU(LSE)}$ is the startup time measured from the moment it is enabled (by software) to a stabilized 32.768 kHz oscillation is reached. This value is guaranteed by characterization. It is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer.

Note: For information on selecting the crystal, refer to the application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.

Table 41. Main PLL characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$I_{DD(PLL)}$(4)	PLL power consumption on VDD	VCO freq = 192 MHz VCO freq = 432 MHz	0.15 0.45	-	0.40 0.75	mA
$I_{DDA(PLL)}$(4)	PLL power consumption on VDDA	VCO freq = 192 MHz VCO freq = 432 MHz	0.30 0.55	-	0.40 0.85	

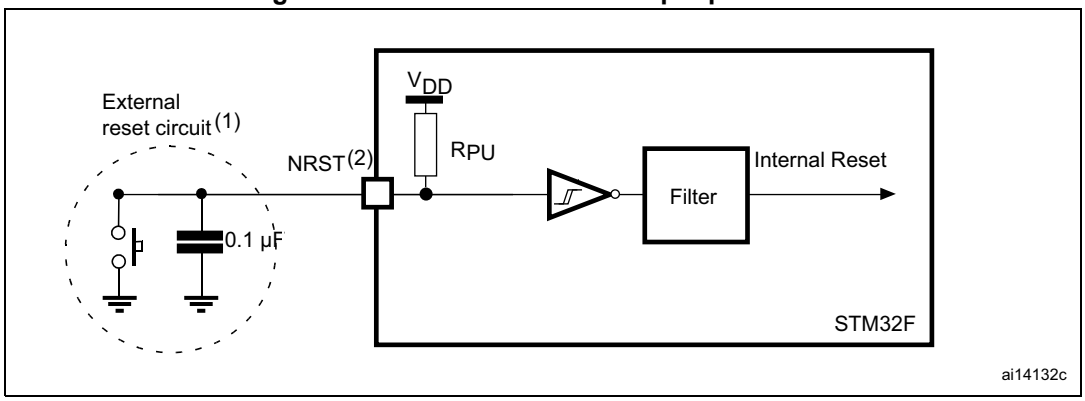
1. Take care of using the appropriate division factor M to obtain the specified PLL input clock values. The M factor is shared between PLL and PLLI2S.
2. Guaranteed by design.
3. The use of 2 PLLs in parallel could degraded the Jitter up to +30%.
4. Guaranteed by characterization.

Table 42. PLLI2S (audio PLL) characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
f_{PLLI2S_IN}	PLLI2S input clock(1)			0.95(2)	1	2.10	MHz
f_{PLLI2S_OUT}	PLLI2S multiplier output clock			-	-	216	
f_{VCO_OUT}	PLLI2S VCO output			192	-	432	
t_{LOCK}	PLLI2S lock time	VCO freq = 192 MHz		75	-	200	µs
		VCO freq = 432 MHz		100	-	300	
Jitter(3)	Master I2S clock jitter	Cycle to cycle at 12.288 MHz on 48 KHz period, N=432, R=5	RMS	-	90	-	ps
			peak to peak	-	±280	-	
		Average frequency of 12.288 MHz N = 432, R = 5 on 1000 samples		-	90	-	
	WS I2S clock jitter	Cycle to cycle at 48 KHz on 1000 samples		-	400	-	
$I_{DD(PLLI2S)}$(4)	PLLI2S power consumption on V_{DD}	VCO freq = 192 MHz VCO freq = 432 MHz		0.15 0.45	-	0.40 0.75	mA
$I_{DDA(PLLI2S)}$(4)	PLLI2S power consumption on V_{DDA}	VCO freq = 192 MHz VCO freq = 432 MHz		0.30 0.55	-	0.40 0.85	

1. Take care of using the appropriate division factor M to have the specified PLL input clock values.
2. Guaranteed by design.
3. Value given with main PLL running.
4. Guaranteed by characterization.

Figure 32. Recommended NRST pin protection



1. The reset network protects the device against parasitic resets.
2. The external capacitor must be placed as close as possible to the device.
3. The user must ensure that the level on the NRST pin can go below the $V_{IL(NRST)}$ max level specified in *Table 57*. Otherwise the reset is not taken into account by the device.

6.3.18 TIM timer characteristics

The parameters given in *Table 58* are guaranteed by design.

Refer to *Section 6.3.16: I/O port characteristics* for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

Table 58. TIMx characteristics(1)(2)

Symbol	Parameter	Conditions(3)	Min	Max	Unit
$t_{res(TIM)}$	Timer resolution time	AHB/APBx prescaler=1 or 2 or 4, $f_{TIMxCLK}$ = 84 MHz	1	-	$t_{TIMxCLK}$
			11.9	-	ns
		AHB/APBx prescaler>4, $f_{TIMxCLK}$ = 84 MHz	1	-	$t_{TIMxCLK}$
			11.9	-	ns
f_{EXT}	Timer external clock frequency on CH1 to CH4	$f_{TIMxCLK}$ = 84 MHz	0	$f_{TIMxCLK}/2$	MHz
			0	42	MHz
Res_{TIM}	Timer resolution		-	16/32	bit
$t_{COUNTER}$	16-bit counter clock period when internal clock is selected	$f_{TIMxCLK}$ = 84 MHz	0.0119	780	µs
t_{MAX_COUNT}	Maximum possible count with 32-bit counter		-	65536 × 65536	$t_{TIMxCLK}$
		$f_{TIMxCLK}$ = 84 MHz	-	51.1	S

1. TIMx is used as a general term to refer to the TIM1 to TIM11 timers.
2. Guaranteed by design.
3. The maximum timer frequency on APB1 is 42 MHz and on APB2 is up to 84 MHz, by setting the TIMPRE bit in the RCC_DCKCFGR register, if APBx prescaler is 1 or 2 or 4, then TIMxCLK = HCKL, otherwise TIMxCLK >= 4x PCLKx.

Table 61. SPI dynamic characteristics(1) (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{v(MO)}$	Data output valid time	Master mode (after enable edge)	-	3	5	ns
$t_{h(MO)}$	Data output hold time	Master mode (after enable edge)	2	-	-	ns

1. Guaranteed by characterization.
2. Maximum frequency in Slave transmitter mode is determined by the sum of $t_{v(SO)}$ and $t_{su(MI)}$ which has to fit into SCK low or high phase preceding the SCK sampling edge. This value can be achieved when the SPI communicates with a master having $t_{su(MI)}$ = 0 while Duty(SCK) = 50%

Figure 34. SPI timing diagram - slave mode and CPHA = 0

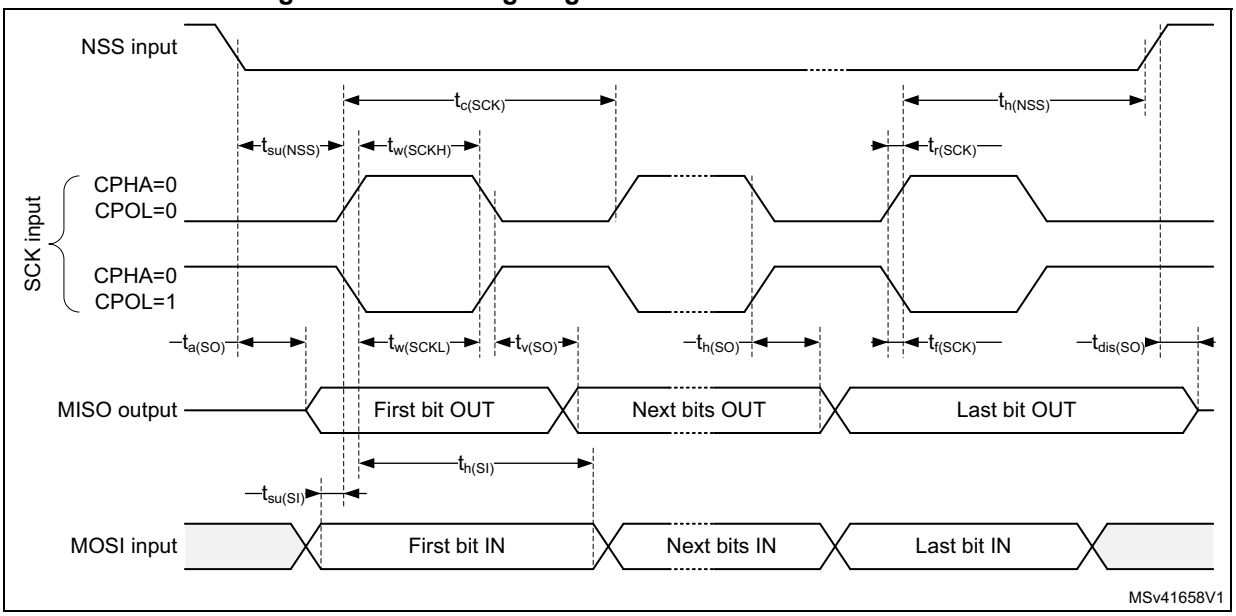


Figure 35. SPI timing diagram - slave mode and CPHA = 1(1)

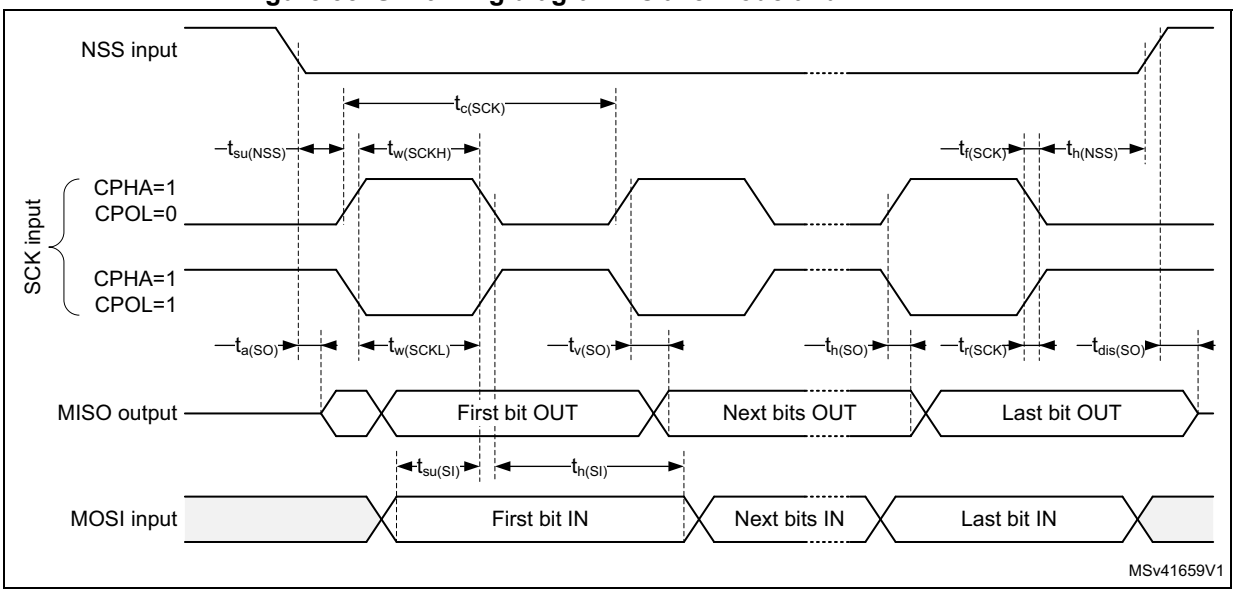
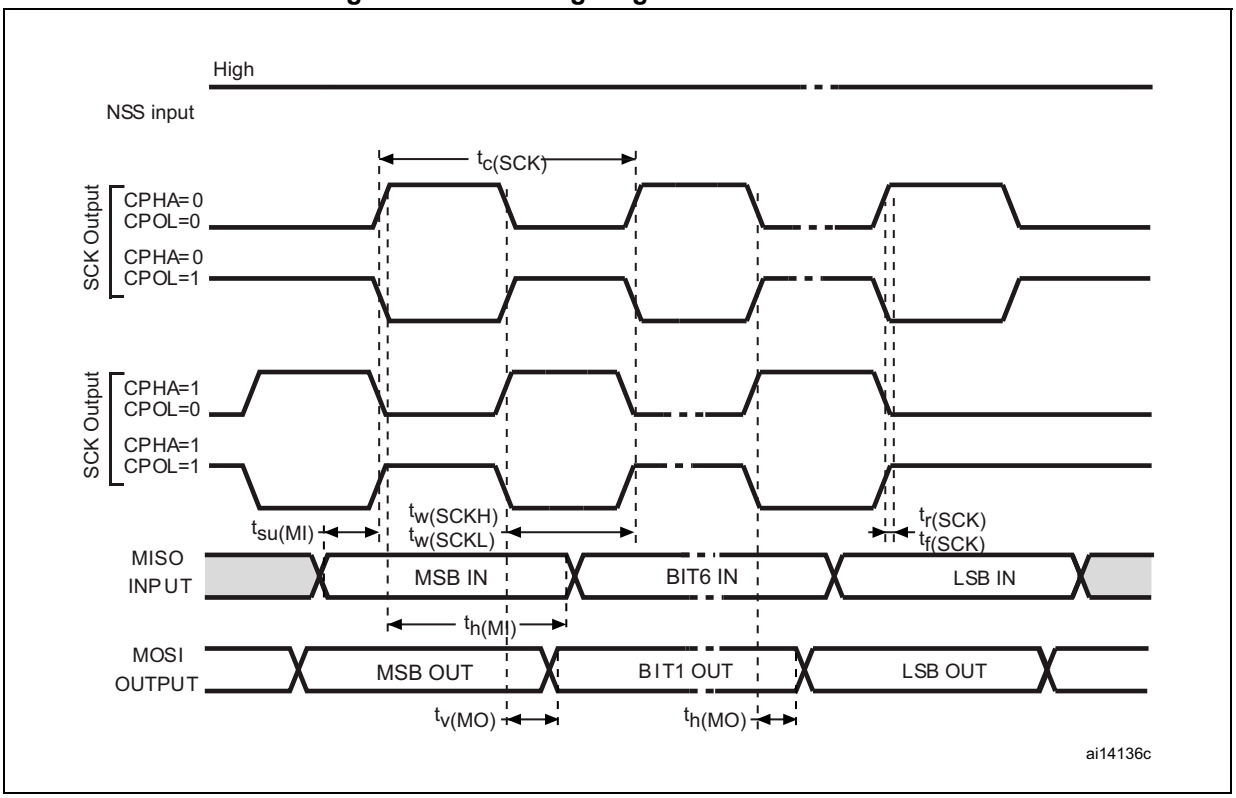


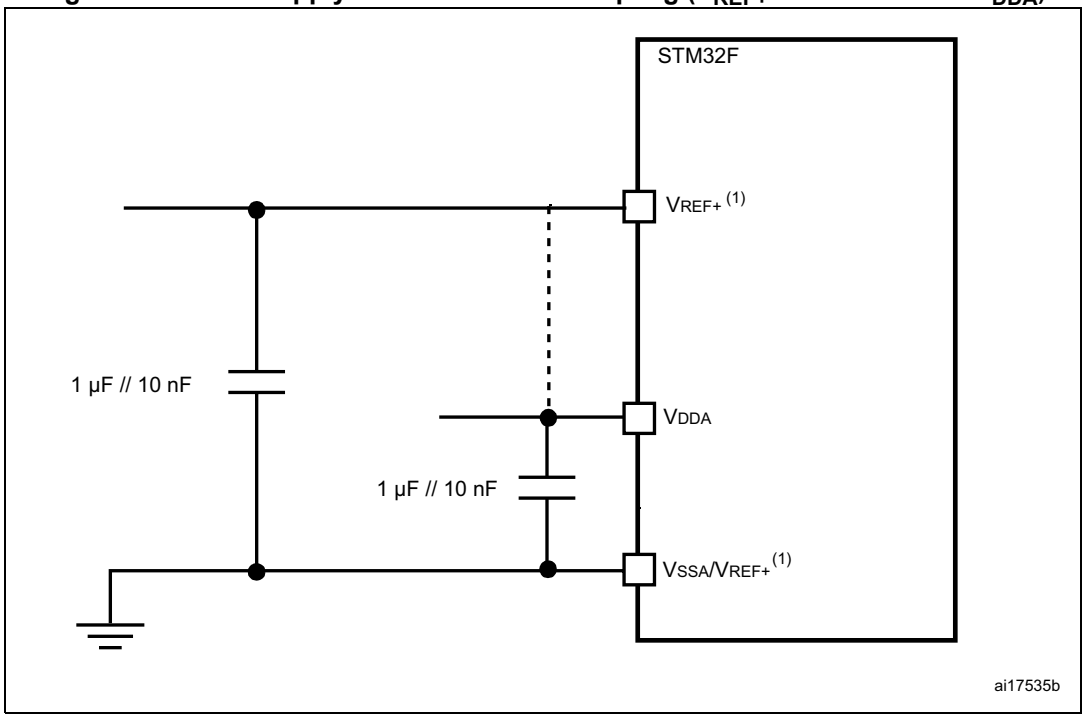
Figure 36. SPI timing diagram - master mode(1)



General PCB design guidelines

Power supply decoupling should be performed as shown in *Figure 42* or *Figure 43*, depending on whether V_{REF+} is connected to V_{DDA} or not. The 10 nF capacitors should be ceramic (good quality). They should be placed them as close as possible to the chip.

Figure 42. Power supply and reference decoupling (V_{REF+} not connected to V_{DDA})



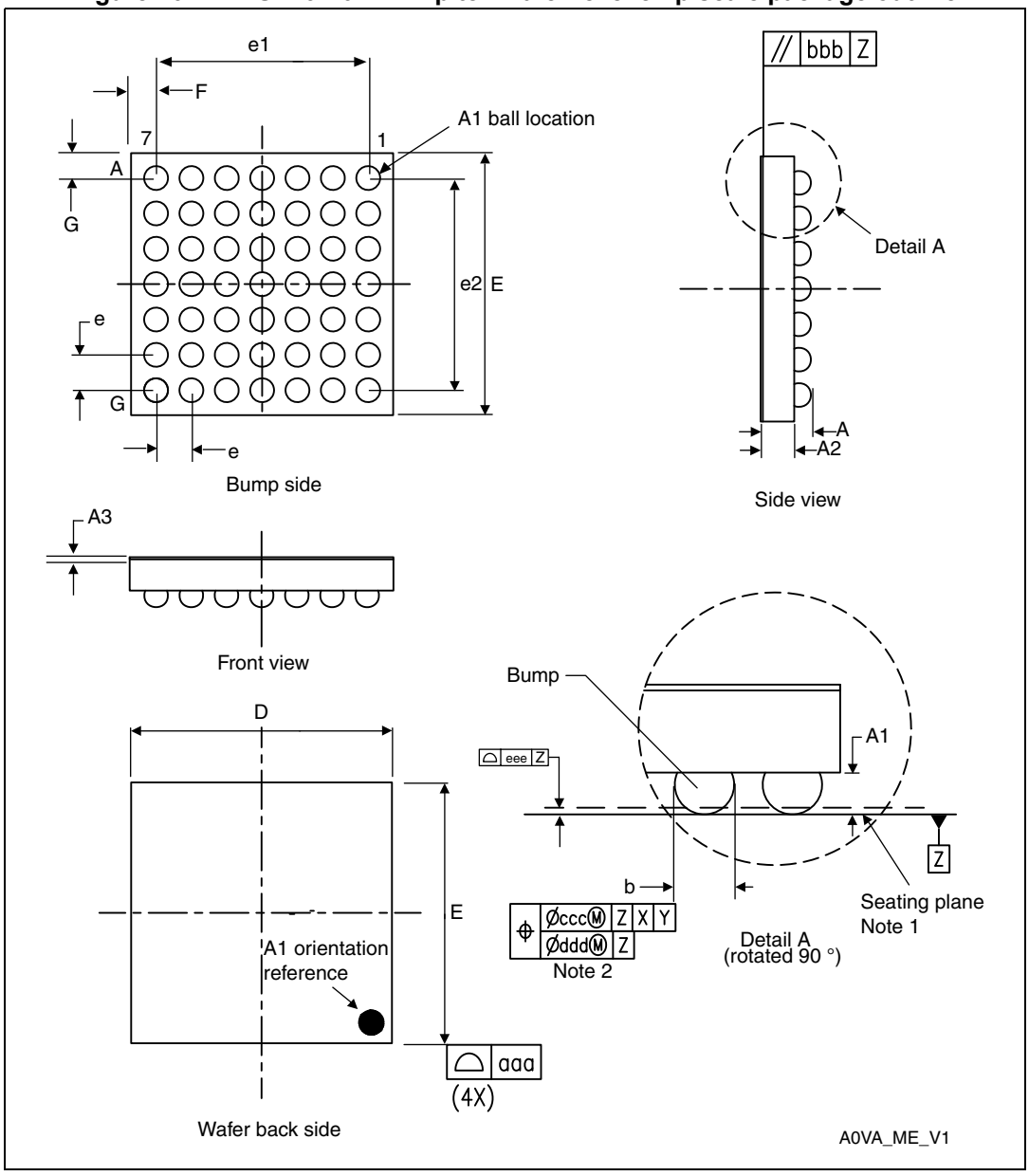
1. V_{REF+} and V_{REF-} inputs are both available on UFBGA100. V_{REF+} is also available on LQFP100. When V_{REF+} and V_{REF-} are not available, they are internally connected to V_{DDA} and V_{SSA}.

7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK® is an ST trademark.

7.1 WLCSP49 2.965x2.965 mm package information

Figure 46. WLCSP49 - 0.4 mm pitch wafer level chip scale package outline



1. Drawing is not to scale.

Table 80. WLCSP49 recommended PCB design rules (0.4 mm pitch)

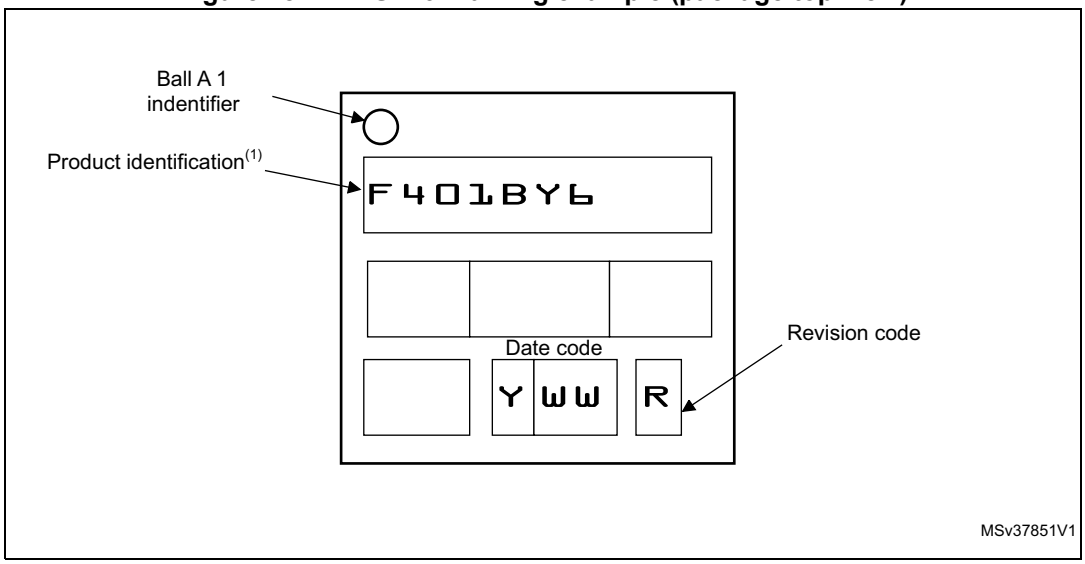
Dimension	Recommended values
Pitch	0.4 mm
Dpad	260 µm max. (circular) 220 µm recommended
Dsm	300 µm min. (for 260 µm diameter pad)
PCB pad design	Non-solder mask defined via underbump allowed

WLCSP49 device marking

The following figure gives an example of topside marking orientation versus ball A1 identifier location.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Figure 48. WLCSP49 marking example (package top view)



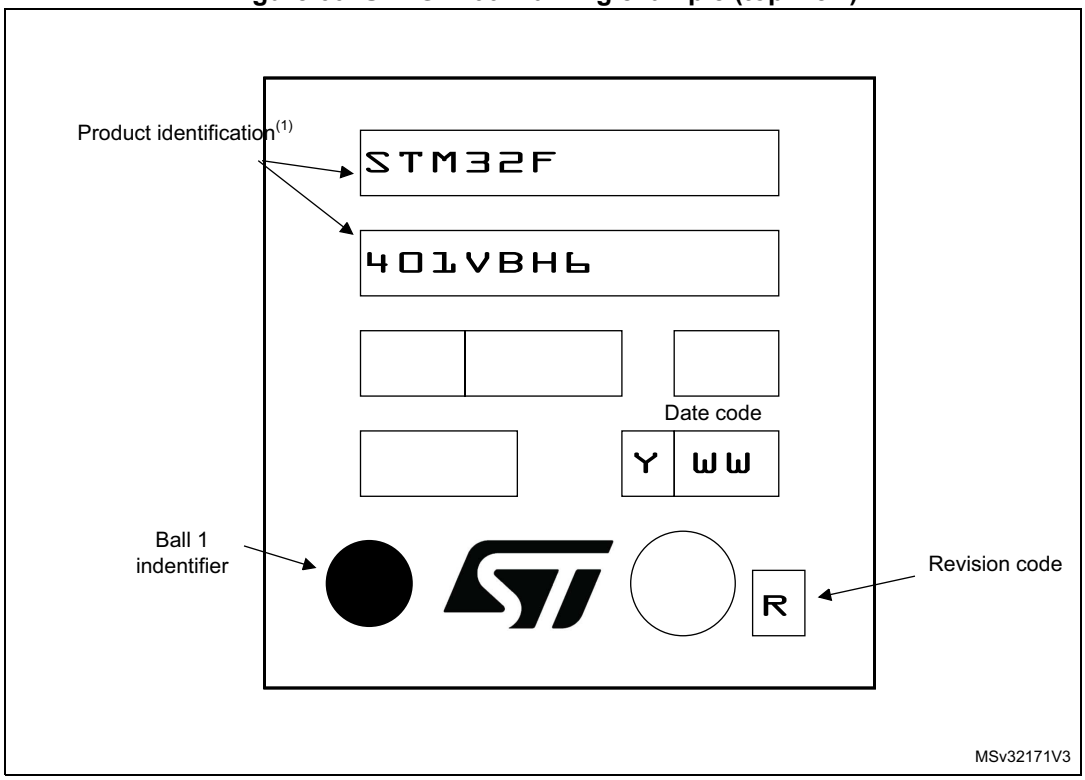
1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

UFBGA100 device marking

The following figure gives an example of topside marking orientation versus ball A1 identifier location.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Figure 60. UFBGA100 marking example (top view)



1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

9 Revision history

Table 88. Document revision history

Date	Revision	Changes
23-Jul-2013	1	Initial release.
06-Sep-2013	2	Updated product status to production data Added I2C 1 MBit/s in *Features* Updated *Figure 1: Compatible board design for LQFP100 package* Added notes and revised the main function after reset columnn *Table 8: STM32F401xB/STM32F401xC pin definitions*. Replaced 'I2S2_CKIN' signal name with 'I2S_CKIN' and added EVENTOUT alternate function in *Table 8: STM32F401xB/STM32F401xC pin definitions* and *Table 9: Alternate function mapping* Updated *Section 3.28: Analog-to-digital converter (ADC)* Updated the reference of $V_{ESD(CDM)}$ in *Table 51: ESD absolute maximum ratings* Updated *Section 3.20: Inter-integrated circuit interface (I2C)*, including *Table 5: Comparison of I2C analog and digital filters* Removed first sentence ("Unless otherwise specified...") in *I2C interface characteristics* Changed the order of the tables in *Section 6.3.6: Supply current characteristics* Modified the "SDA and SCL rise time" fast mode I2C minimum value in *Table 59: I^2C characteristics* Updated *Figure 33: I^2C bus AC waveforms and measurement circuit* and *Table 60: SCL frequency (f_{PCLK1}= 42 MHz, V_{DD} = V_{DD_I2C} = 3.3 V)* Replaced "Marking of engineering samples" sections with "Marking of samples" sections, and added *UFBGA100 device marking* section for package UFGBA100 in *Section 7: Package information*
08-Nov-2013	3	Updated UFBGA100 in *Table 86: Package thermal characteristics*. Changed WLCSP49 package measurements to 3 x 3 mm in *Section 7.1*.